



Dual P-Channel 20 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
- 20	$0.490 \text{ at V}_{GS} = -4.5 \text{ V}$	- 1.3 ^a			
	0.640 at V _{GS} = - 2.5 V	- 1.2	1.6 nC		
	0.790 at V _{GS} = - 1.8 V	- 1.0			

FEATURES

 Halogen-free According to IEC 61249-2-21 Definition

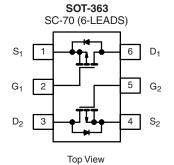
Compliant to RoHS Directive 2002/95/EC

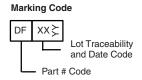
- TrenchFET[®] Power MOSFET
- · PWM Optimized
- ·

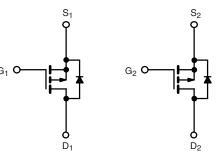




· Load Switch for Portable Devices







Ordering Information: Si1967DH-T1-E3 (Lead (Pb)-free)

Si1967DH-T1-GE3 (Lead (Pb)-free and Halogen-free)

P-Channel MOSFET P-Channel MOSFET

ABSOLUTE MAXIMUM RATIN	IGS T _A = 25 °C,	unless othe	erwise noted		
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V_{DS}	- 20	V	
Gate-Source Voltage		V_{GS}	± 8	V	
	T _C = 25 °C		- 1.3 ^a		
Continuous Drain Current /T 150 °C)	T _C = 70 °C	I _D	- 1.1		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C		- 1.0 ^{b, c}		
	T _A = 70 °C	1	- 0.83 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	- 3		
	T _C = 25 °C		- 1		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	- 0.6 ^{b, c}		
Maximum Power Dissipation	T _C = 25 °C	P _D	1.25		
	T _C = 70 °C		0.8	W	
	T _A = 25 °C		0.74 ^{b, c}	VV	
	T _A = 70 °C	1	0.47 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R_{thJA}	130	170	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	80	100		

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 5 s
- d. Maximum under steady state conditions is 220 °C/W.

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SPECIFICATIONS T _J = 25 °C, unless otherwise noted							
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 20			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	_S /T _J I _D = - 250 µA		- 20		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			2			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \mu A$	- 0.4		- 1.0	V	
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 8 V			± 100	nA	
Zava Cata Valtaga Dvain Curvent		V _{DS} = - 20 V, V _{GS} = 0 V			- 1	μΑ	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 85 ^{\circ}\text{C}$			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 V$, $V_{GS} = -4.5 V$	- 3			Α	
		V _{GS} = - 4.5 V, I _D = - 0.91 A		0.390	0.490		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -2.5 \text{ V}, I_D = -0.8 \text{ A}$		0.500	0.640	Ω	
	, ,	V _{GS} = - 1.8 V, I _D = - 0.25 A		0.640	0.790	1	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 0.91 A		2		S	
Dynamic ^b	•		I.	•	,	,	
Input Capacitance	C _{iss}			110		pF	
Output Capacitance	C _{oss}	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		26			
Reverse Transfer Capacitance	C _{rss}			16			
T. 10 . 0	Q _g	V _{DS} = - 10 V, V _{GS} = - 8 V, I _D = - 1.1 A		2.6	4.0	nC	
Total Gate Charge		V _{DS} = - 10 V, V _{GS} = - 4.5 V, I _D = - 1.1 A		1.6	2.4		
Gate-Source Charge				0.36			
Gate-Drain Charge	Q _{gd}			0.33			
Gate Resistance	R _g	f = 1 MHz		7.5		Ω	
Turn-On Delay Time	t _{d(on)}			12	20	ns	
Rise Time	t _r	$V_{DD} = -10 \text{ V}, R_1 = 12 \Omega$		27	40		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -0.83 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		15	25		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			2	5		
Rise Time	t _r	$V_{DD} = -10 \text{ V, R}_{L} = 12 \Omega$		12	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong -0.83 \text{ A}, V_{GEN} = -8 \text{ V}, R_g = 1 \Omega$		12	20		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristic			L	l	L	L	
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			- 1.0		
Pulse Diode Forward Current ^a	I _{SM}				- 3.0	A	
Body Diode Voltage	V _{SD}	I _S = - 0.9 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	3		25	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			15	30	nC	
Reverse Recovery Fall Time	t _a	$I_F = -0.83 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		12		<u> </u>	
Reverse Recovery Rise Time	t _b			13		ns	
•			l	1	1	1	

Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

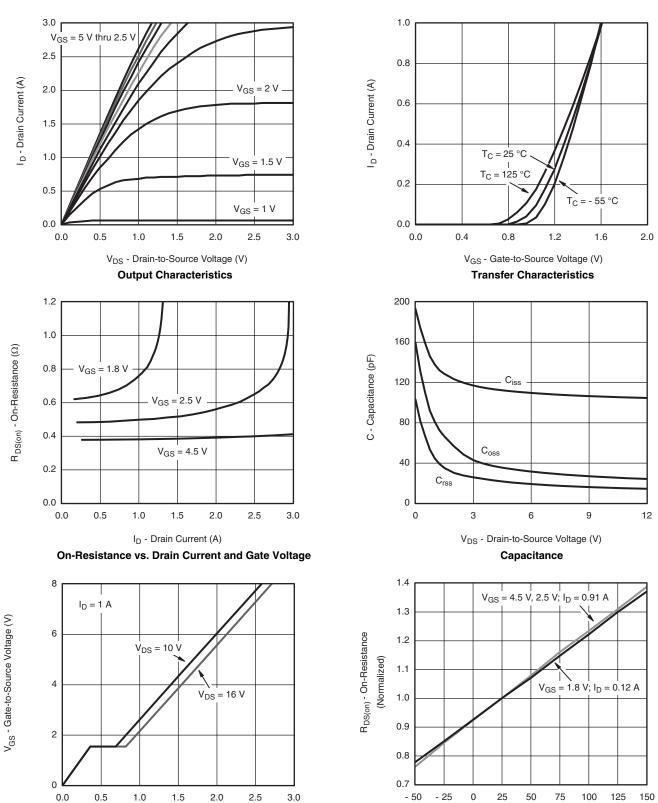
a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



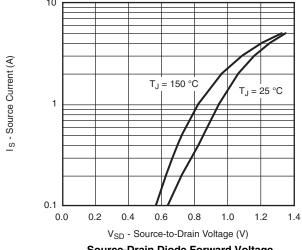
Q_g - Total Gate Charge (nC)

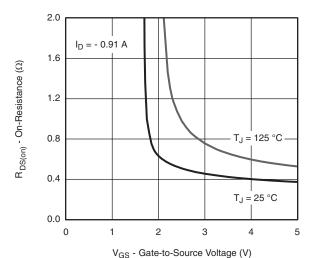
Gate Charge

 $\label{eq:TJ-Junction} T_{J} \text{ - Junction Temperature (°C)}$ On-Resistance vs. Junction Temperature

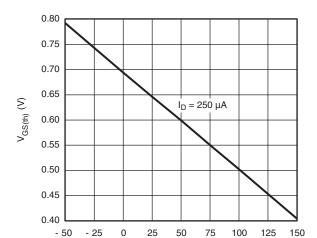
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

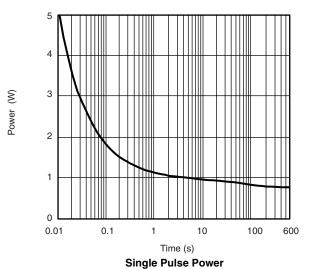




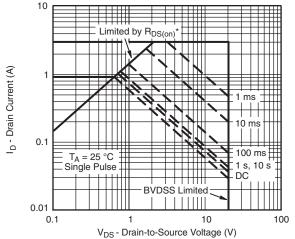
Source-Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage



T_J - Temperature (°C) **Threshold Voltage**

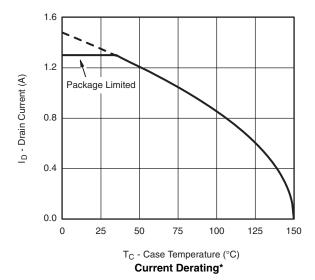


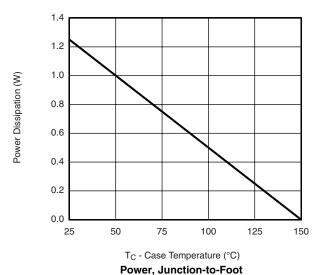
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



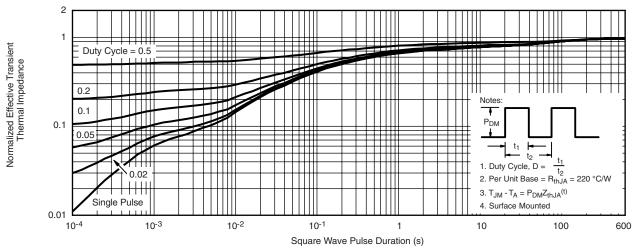


^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

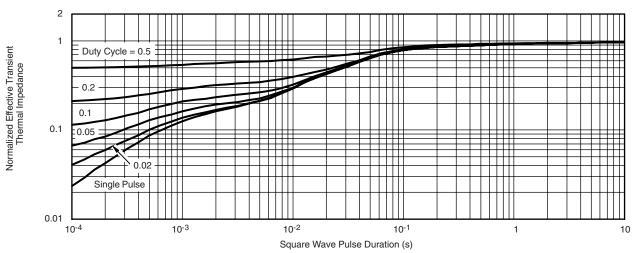
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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

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